

## N-Channel 600V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	600			
R <sub>DS(on)</sub> max. at 25 °C (Ω)	V <sub>GS</sub> = 10 V 0.15			
Q <sub>g</sub> max. (nC)	70			
Q <sub>gs</sub> (nC)	7.8			
Q <sub>gd</sub> (nC)	9			
Configuration	Single			

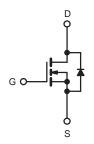
D2PAK (TO-263)

#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial



N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V <sub>DS</sub>	600	V
Gate-Source Voltage			$V_{GS}$	± 30	v
Continuous Drain Current (T,I = 150 °C)	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25  ^{\circ}{\rm C}$ $T_{\rm C} = 100  ^{\circ}{\rm C}$	I <sub>D</sub>	20	
Continuous Drain Current (1) = 150 °C)		T <sub>C</sub> = 100 °C		10	А
Pulsed Drain Current a			I <sub>DM</sub>	62	
Linear Derating Factor				1.67	W/°C
Single Pulse Avalanche Energy b			E <sub>AS</sub>	485	mJ
Maximum Power Dissipation			P <sub>D</sub>	205/35	W
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Drain-Source Voltage Slope T <sub>J</sub> = 125 °C			d\//d±	37	1//20
Reverse Diode dV/dt d			dV/dt	4.5	- V/ns
Soldering Recommendations (Peak Temperature) c for 10 s				300	°C

- a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD}=50$  V, starting  $T_J=25$  °C, L=28.2 mH,  $R_g=25$   $\Omega$ ,  $I_{AS}=4.5$  A. c. 1.6 mm from case.

- d.  $I_{SD} \le I_D$ , dI/dt = 100 A/ $\mu$ s, starting  $T_J = 25$  °C.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	°C/W		
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.7	C/VV		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		-					•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 250 μA	600	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.75	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2	-	4	V
			V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Gate-Source Leakage	$I_{GSS}$		V <sub>GS</sub> = ± 30 V	-	_	± 1	μΑ
			= 600 V, V <sub>GS</sub> = 0 V	-	-	1	
Zero Gate Voltage Drain Current	$I_{DSS}$		/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	_	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 8 A	-	0.15	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	s = 30 V, I <sub>D</sub> = 8 A	-	5.6	-	S
Dynamic		•					
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V$ ,		-	1440	-	pF
Output Capacitance	Coss	7	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$		80	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1 MHz		-	4	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	63	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	213	-	
Total Gate Charge	Qg			-	48	96	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 8 \text{ A}, V_{DS} = 520 \text{ V}$		11	-	nC
Gate-Drain Charge	Q <sub>gd</sub>				21	_	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD}$ = 520 V, $I_{D}$ = 8 A, $V_{GS}$ = 10 V, $R_{q}$ = 9.1 Ω		-	18	25	
Rise Time	t <sub>r</sub>			-	24	55	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	48	70	ns
Fall Time	t <sub>f</sub>		1		25	40	
Gate Input Resistance	$R_g$	f = 1 MHz, open drain		-	0.8	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	20	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	60	- A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 8 A, V <sub>GS</sub> = 0 V		-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 8 A,		-	475	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	5.8	-	μC
Reverse Recovery Current	I <sub>RRM</sub>	dl/dt = 100 A/ $\mu$ s, $V_R$ = 400 V			35	_	A

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

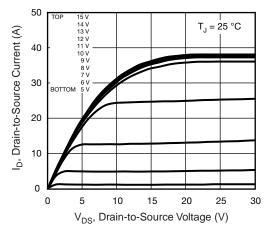


Fig. 1 - Typical Output Characteristics

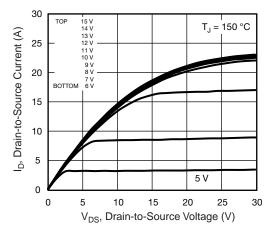


Fig. 2 - Typical Output Characteristics

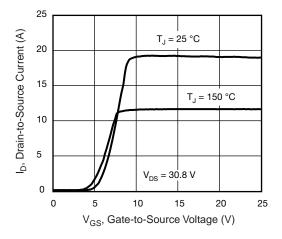


Fig. 3 - Typical Transfer Characteristics

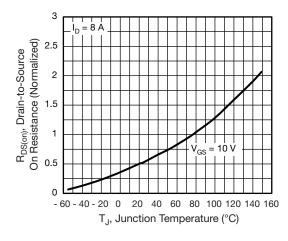


Fig. 4 - Normalized On-Resistance vs. Temperature

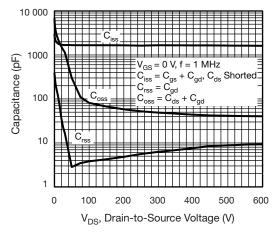


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

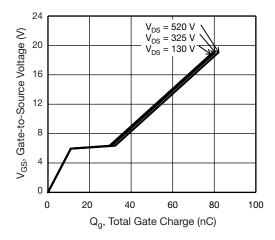


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



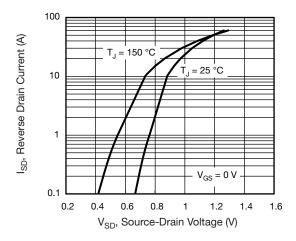


Fig. 7 - Typical Source-Drain Diode Forward Voltage

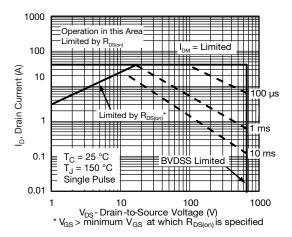


Fig. 8 - Maximum Safe Operating Area

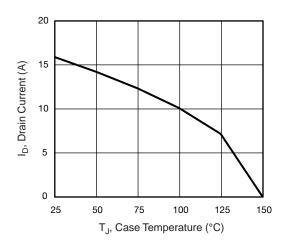


Fig. 9 - Maximum Drain Current vs. Case Temperature

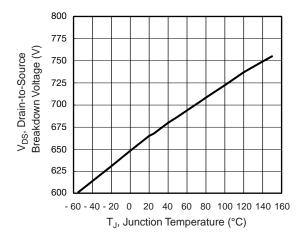


Fig. 10 - Temperature vs. Drain-to-Source Voltage

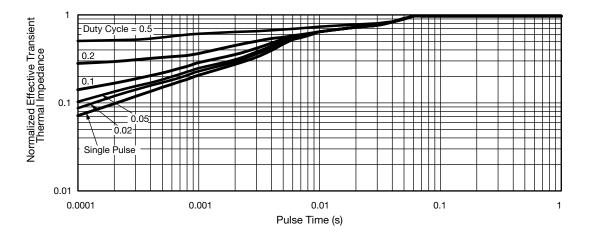


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



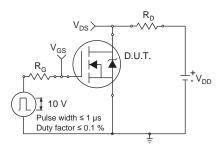


Fig. 12 - Switching Time Test Circuit

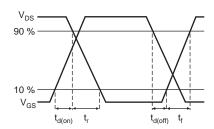


Fig. 13 - Switching Time Waveforms

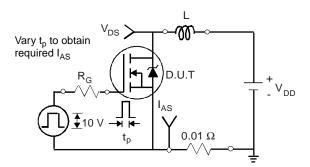


Fig. 14 - Unclamped Inductive Test Circuit

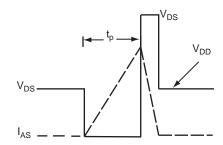


Fig. 15 - Unclamped Inductive Waveforms

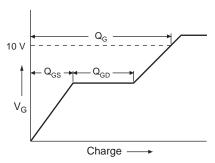


Fig. 16 - Basic Gate Charge Waveform

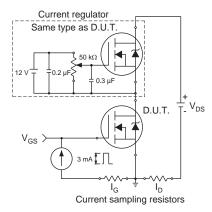
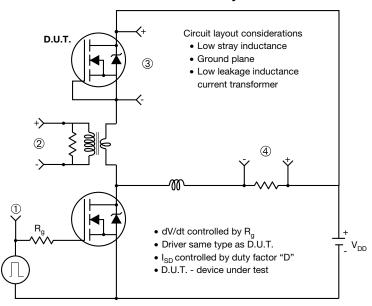


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



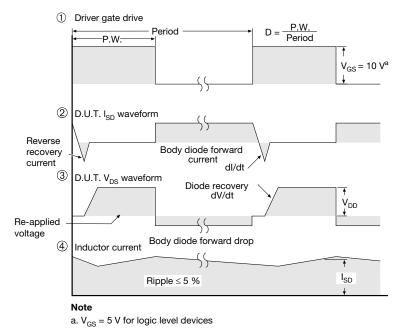
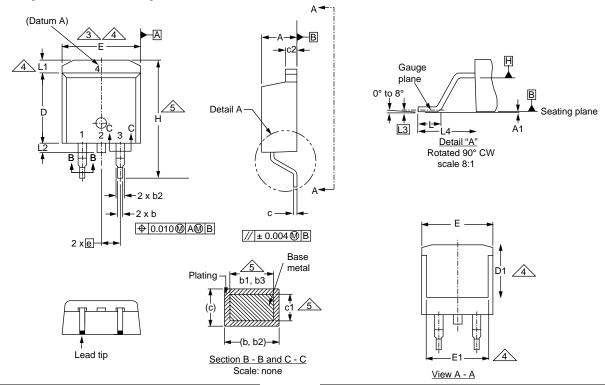


Fig. 18 - For N-Channel



#### **TO-263AB (HIGH VOLTAGE)**



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
D1	6.86	-	0.270	-	
E	9.65	10.67	0.380	0.420	
E1	6.22	-	0.245	-	
е	2.54	BSC	0.100 BSC		
Н	14.61	15.88	0.575	0.625	
L	1.78	2.79	0.070	0.110	
L1	-	1.65	-	0.066	
L2	-	1.78	-	0.070	
L3	0.25 BSC		0.010 BSC		
L4	4.78	5.28	0.188	0.208	

ECN: S-82110-Rev. A, 15-Sep-08

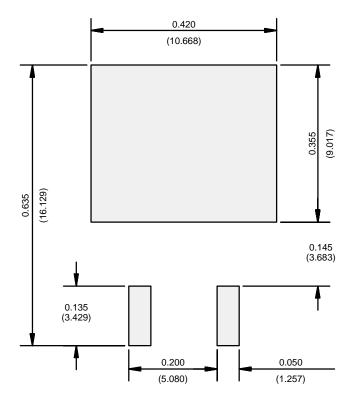
DWG: 5970

#### Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.



### RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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